

<b>Notice of References Cited</b>	Application/Control No. 09/994,395	Applicant(s)/Patent Under Reexamination LOPATIN ET AL.	
	Examiner Thomas J. Magee	Art Unit 2811	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,243,222	09-1993	James M. E. Harper et al.	257/774
	C	US-6,090,710	07-2000	Panayotis Constantinou Andricacos et al.	438/687
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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	U	James A. Cunningham, "Improving Copper Interconnects: A Search for Useful Dopants," Semiconductor International, (April. 2000), pp. 1-8.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.